DATA SHEET



μ**ΡΑ1550**

N-CHANNEL POWER MOS FET ARRAY FOR SWITCHING

 μ PA1550 is a N-channel vertical power MOS FET and this switching device is available for direct drive by output of 5 V power supply IC.

This device features low on-resistance and excellent switching characteristic, and is ideal for control of devices such as mortars, solenoid, or ramp.

FEATURES

- Gate drive available at logic level (VGS = 4 V)
- High current capacity and low on-resistnace $I_{D(pulse)} = \pm 20 \text{ A}$ $R_{DS(on)} = 0.09 \Omega \text{ TYP}. @V_{GS} = 10 \text{ V}$ $R_{DS(on)} = 0.11 \Omega \text{ TYP}. @V_{GS} = 4 \text{ V}$

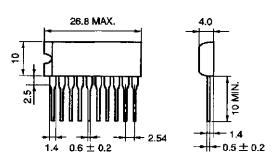
- Easy to mount the printing board due to 2.54 mm (0.1 inch) interval of lead pins
- Small dimension and no electrode exposure except lead pins enable the high density mounting.

ORDERING INFORMATION

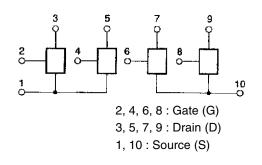
| Part Number | Package | Quality |
|-------------|------------|----------|
| μPA1550H | 10-pin SIP | Standard |

Please refer to "Quality Grades on NEC Semiconductor Devices" (Document No. C11531E) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

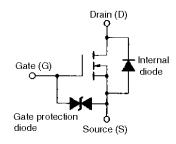
PACKAGE DRAWING (UNIT: mm)



ELECTRODE CONNECTION



INTERNAL EQUIVALENT CIRCUIT



The information in this document is subject to change without notice. Before using this document, please confirm that this is the latest version. Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

ABSOLUTE MAXIMUM RATINGS (Ta = 25°C)

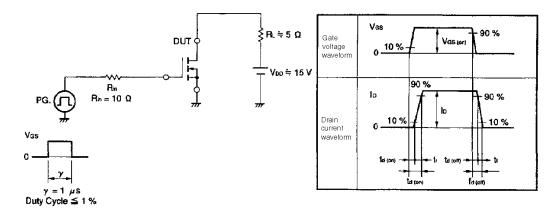
| Parameter | Symbol | Conditions | Ratings | Unit |
|-------------------------|----------|--|-------------|--------|
| Drain to source voltage | VDSS | V _{GS} = 0 | 30 | V |
| Gate to source voltage | Vgss | V _{DS} = 0 | ±20 | V |
| Drain current (DC) | D(DC) | Tc = 25°C | ±5 | A/unit |
| Drain current (pulse) | D(pulse) | $PW \le 10 \ \mu s$ duty cycle $\le 1 \ \%$ | ±20 | A/unit |
| Total power dissipation | PT1* | Tc = 25°C | 3.5 | W |
| Total power dissipation | PT2* | Ta = 25°C | 28 | W |
| Channel temperature | Tch | | 150 | °C |
| Storage temperature | Tstg | | -55 to +150 | °C |

* When all 4 elements are ON.

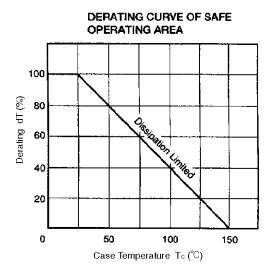
ELECTRICAL CHARACTERISTICS (VCC = 5V, Ta = 25°C)

| Parameter | Symbol | Conditions | MIN. | TYP. | MAX. | Unit |
|-------------------------------------|----------------------|--|------|------|------|------|
| Drain cutoff current | IDSS | $V_{\text{DS}} = 30 \text{ V}, \text{ V}_{\text{GS}} = 0 \text{ V}$ | | | 10 | μA |
| Gate leakage current | lgss | $V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$ | | | ±100 | nA |
| Gate cutoff voltage | V _{GS(off)} | $V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ mA}$ | 0.8 | | 2.5 | V |
| Forward transfer admittance | y _{ts} | V _{DS} = 10 V, I _D = 3 A | 4.0 | 5.0 | | S |
| Drain to source on-state resistance | RDS(on)1 | $V_{GS} = 10 \text{ V}, \text{ Id} = 3 \text{ A}$ | | 90 | 100 | mΩ |
| Drain to source on-state resistance | RDS(on)2 | $V_{GS} = 4 \text{ V}, \text{ Id} = 3 \text{ A}$ | | 110 | 150 | mΩ |
| Input capacitance | Ciss | V _{DS} = 10 V | | 900 | | pF |
| Output capacitance | Coss | V _{GS} = 0 V | | 400 | | pF |
| Return capacitance | Crss | f = 1 MHz | | 100 | | pF |
| Turn-on delay time | td(on) | $I_D = 3 A$ | | 10 | | ns |
| Rise time | tr | $V_{GS(on)} = 10 V$ $V_{DD} = 5 \Omega$ $R_{L} = 5 \Omega,$ $R_{in} = 10 \Omega$ | | 40 | | ns |
| Turn-off delay time | td(off) | | | 110 | | ns |
| Fall time | tr | Refer to the test circuit. | | 30 | | ns |

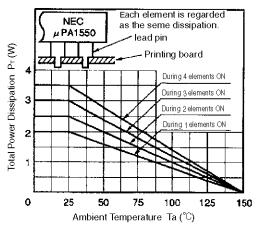
TEST CIRCUIT DIAGRAM: SWITCHING TIME



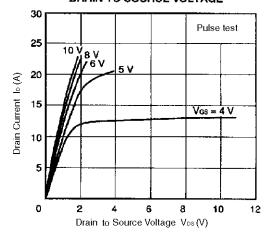
TYPICAL CHARACTERISTICS (Ta = 25°C)

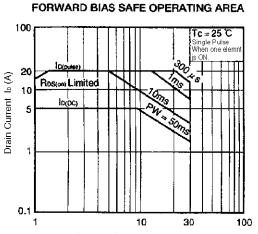






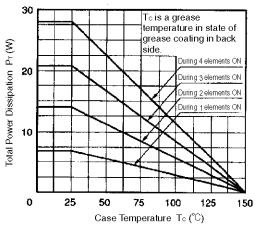




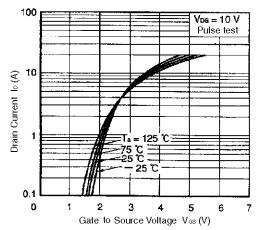


Drain to Source Voltage Vos (V)

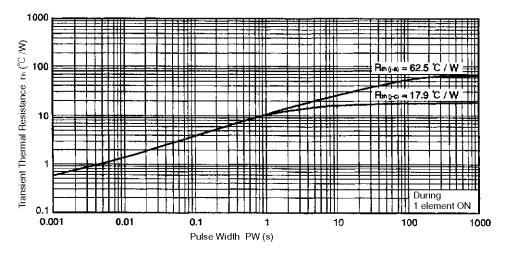
TOTAL POWER DISSIPATION vs. CASE TEMPERATURE



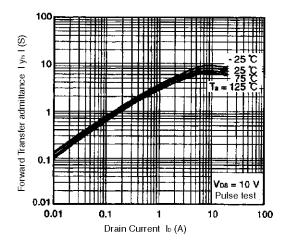
TRANSFER CHARACTERISTICS

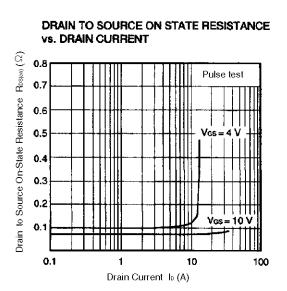


TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

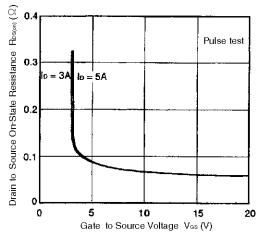


FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT

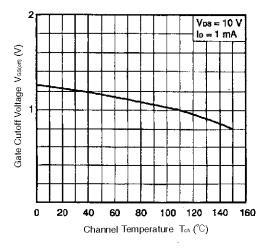




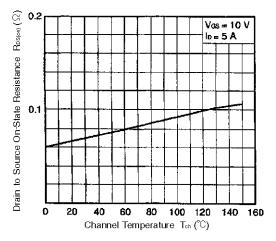
DRAIN TO SOURCE ON STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



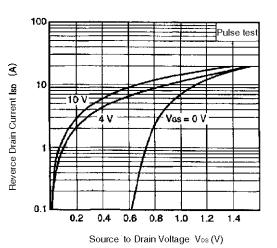
GATE TO SOURCE CUTOFF VOLTAGE vs. CHANNEL TEMPERATURE



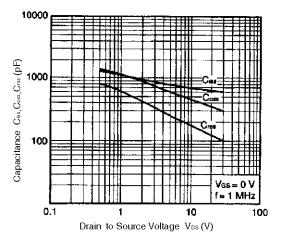
DRAIN TO SOURCE ON - STATE RESISTANCE vs. CHANNEL TEMPERATURE



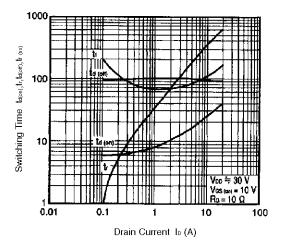
BODY DIODE FORWARD VOLTAGE



CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



SWITCHING CARACTERISTICS



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